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## EUROPEAN STANDARD NORME EUROPÉENNE EUROPÄISCHE NORM

### EN 60749-18

February 2003

ICS 31.080.01

English version

### Semiconductor devices – Mechanical and climatic test methods Part 18: Ionizing radiation (total dose) (IEC 60749-18:2002)

Dispositifs à semiconducteurs – Méthodes d'essais mécaniques et climatiques Partie 18: Rayonnements ionisants (dose totale) (CEI 60749-18:2002) Halbleiterbauelemente – Mechanische und klimatische Prüfverfahren Teil 18: Ionisierende Strahlung (Gesamtdosis) (IEC 60749-18:2002)

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# CENELEC

European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

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#### Foreword

The text of document 47/1657/FDIS, future edition 1 of IEC 60749-18, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60749-18 on 2003-02-01.

The following dates were fixed:

-	latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2003-11-01
_	latest date by which the national standards conflicting with the EN have to be withdrawn	(dow)	2006-02-01

#### **Endorsement notice**

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